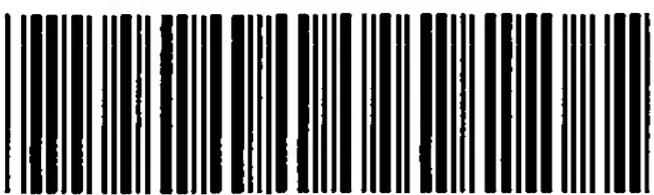


## **Search Notes**



<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
10/662,003	LEE ET AL.
<b>Examiner</b>	<b>Art Unit</b>
Young J. Kim	1637

# **SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interference Search History - see print out		11/7/2007	YJK